

SEM vs. FIB solutions:

- 1) Any atoms that are smaller than half of a wavelength of light are too small to see with a light microscope.
- 2) 0.4nm at 30kV
- 3) SEM uses a beam of electrons and can produce a high resolution image of the sample. FIB uses a finely focused beam of gallium ions for ion milling or deposition of material, circuit editing or imaging a sample.
- 4) At high beam currents, sputtering is induced meaning the FIB is performing precise ion milling and deposition, while at low beam currents sample imaging can be done.